Search	Notes



Application/Control No.	Applicant(s)/Patent under
Application/Control No.	Applicant(s)/ atent under
	Reexamination
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10/520,028 Examiner

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SEARCHED			
Class	Subclass	Date	Examiner
375	260	2/12/2008	L.M.
375	148	2/12/2008	L.M.
375	219	2/12/2008	L.M.
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INTERFERENCE SEARCHED			
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SEARCH (INCLUDING SEAR		
	DATE	EXMR
EAST	2/12/2008	L.M.
IEEE	2/12/2008	L.M.
GOOGLE	2/12/2008	L.M.
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